

Jandel Engineering Limited



Jandel wafer measurement system

Jandel Engineering Limited offers the RM3000+ test unit in combination with the Multiposition Probe stand as a solution for measurements of wafers up to 200mm diameter.

The probe is available in two sizes at the same cost. One size is for wafers up to 150mm diameter and the second for wafers up to 200mm diameter. If small sized wafers are to be measured, the smaller version is more suitable for placement of the wafers on the measurement table. The Θ movement clicks in four positions at 90 degrees and the linear movement in up to 10 positions. These two factors give repeat placement accuracy of +/- 1mm.

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The RM3000+ supplies constant currents between 10nA and 100mA, and measures voltages from 0.001mV to 1000mV. For sheet resistance measurements, the quoted range is 1 milliohm/square to 100 Megohms/square. For volume (bulk) resistivity measurements, the quoted range is 1 milliohm.cm to 1 x 10⁶ ohm.cm. Measurements outside these ranges may be possible, but will depend on the type of sample.

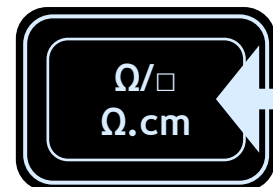
Max. sample size	150mm wafer (200mm wafer on request at no extra cost)
Max. sample thickness	Samples up to 4mm thick can be measured
Microswitch	Prevents current flow when probe is not in contact with sample
Manual control	Simple lever operation for probe contact and removal
Simple set up	Single wire connects probe stand and RM3000+
X - Θ stage	Repositioning accuracy of +/- 1mm
Measurement range	1 mohm/square - 100 Megohms/square, 1 mohm.cm - 1 Megohm.cm
RM3000+ units	mV ohm/square ohm.cm (wafers) ohm.cm (volume)
RM3000+ software	For operation and data control. Supplied free of charge

System configuration

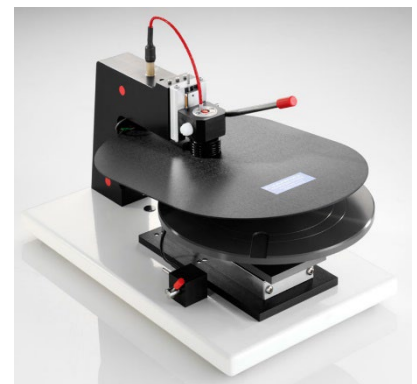
Component parts:

- A. Multiposition Probe stand - 1 pc
- B. Four point probe head - 1 pc
- C. Connecting cable - 1 pc
- D. RM3000+ test unit - 1 pc

Note: Our wafer measurement system includes a cylindrical four point probe head. For more information on cylindrical probe heads and the specifications available, please see our cylindrical probe head datasheet.



Easy unit selection



If you require any further information on the Jandel wafer measurement system, please do not hesitate to contact us using the details below.